Inventor: Matthew R. Williams Title: PROCESS PARAMETER MONITORING SYSTEM AND METHOD OF USE

Our Ref.: MCK-100US Customer No. 23122

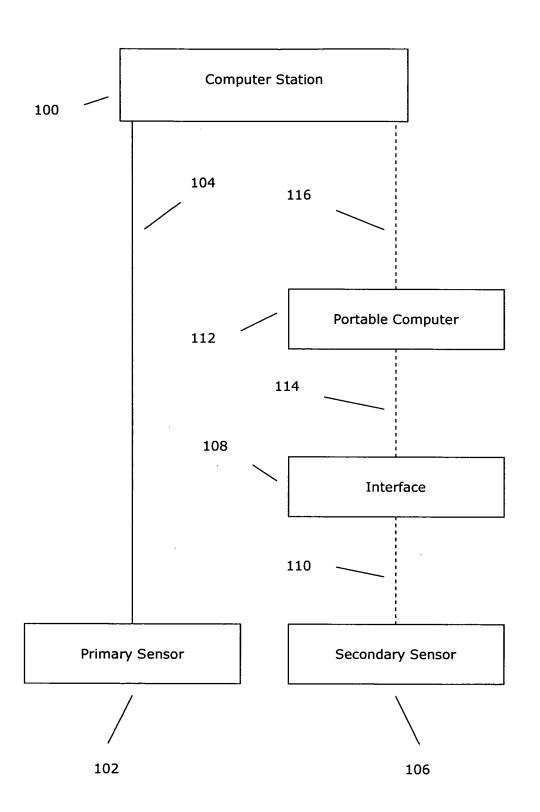


Figure 1

Inventor: Matthew R. Williams
Title: PROCESS PARAMETER MONITORING SYSTEM AND

METHOD OF USE

Our Ref.: MCK-100US Customer No. 23122

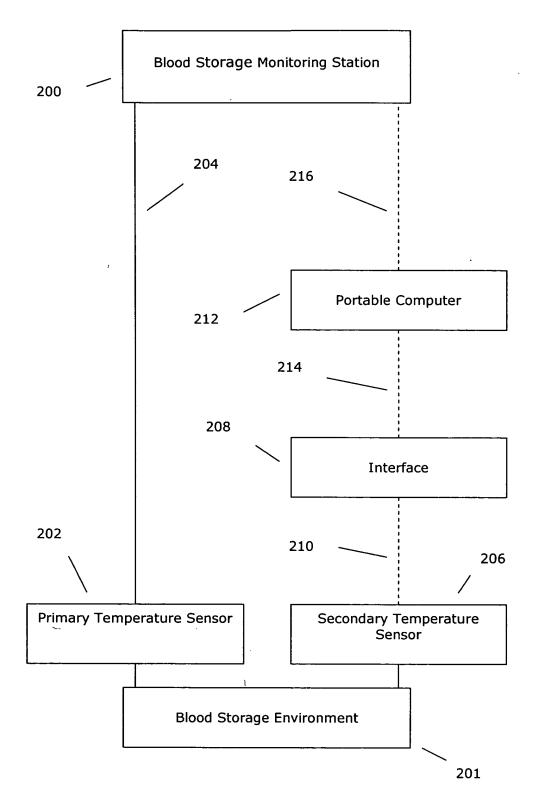


Figure 2

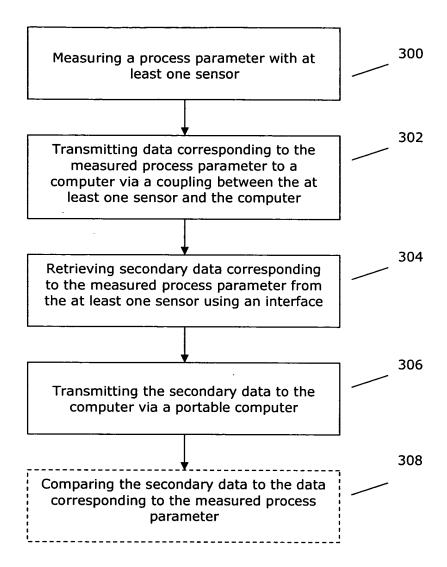
Inventor: Matthew R. Williams

Title: PROCESS PARAMETER MONITORING SYSTEM AND

METHOD OF USE

Our Ref.: MCK-100US Customer No. 23122

Figure 3



Inventor: Matthew R. Williams

Title: PROCESS PARAMETER MONITORING SYSTEM AND

METHOD OF USE

Our Ref.: MCK-100US Customer No. 23122

Figure 4

